## Notice of References Cited Application/Control No. 10/666,646 Examiner John R. Schnurr Applicant(s)/Patent Under Reexamination BASAWAPATNA ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,699,105 A	12-1997	Chen et al.	725/120
*	В	US-5,721,829 A	02-1998	Dunn et al.	725/87
*	С	US-5,729,281 A	03-1998	Utsumi et al.	725/119
*	D	US-5,740,075 A	04-1998	Bigham et al.	709/229
*	E	US-5,828,403 A	10-1998	DeRodeff et al.	725/131
*	F	US-6,188,871 B1	02-2001	Kitamura et al.	725/120
*	G	US-6,192,399 B1	02-2001	Goodman, David D.	725/78
*	Н	US-6,317,885 B1	11-2001	Fries, Robert M.	725/109
*	ı	US-2002/0019984 A1	02-2002	Rakib, Selim Shlomo	725/111
*	J	US-2002/0073431 A1	06-2002	Nikolich, Paul E.	725/111
*	К	US-6,519,773 B1	02-2003	Ahmed et al.	725/118
3	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р			2 20		
	Q					
	R				·	
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.